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Patent
Docket No. 260/085 (7010052001)

Please replace the abstract with the attached abstract.

ABSTRACT

B2 [0112] A hierarchical test control network for an integrated circuit includes a top-level test control circuit block having a chip access port (CAP) controller. The hierarchical test control network also has multiple lower-level test control circuit blocks connected to the top-level test control circuit block in a hierarchical structure. Each of the lower-level test control circuit blocks are a socket access port (SAP) controller. Test operation is transferred downward and upwards within said hierarchical structure.